

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

205109 US 20 DIV

SERIAL NO.

new appl.

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Paul ENQUIST

FILING DATE

Herewith

GROUP

not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
W	AA	5,387,807	02/07/95	Burhan BAYRAKTAROGU			
W	AB	5,943,577	08/24/99	Walter CONTRATA, et al.			
W	AC	5,856,209	01/05/99	Kenji IMANISHI			
W	AD	5,684,308	11/04/97	Michael L. LOVEJOY, et al.			
W	AE	5,648,294	07/15/97	Burhan BAYRAKTAROGU			
W	AF	5,552,617	09/03/96	Darrell G. HILL, et al.			
W	AG	5,512,496	04/30/96	Hin F. CHAU, et al.			
W	AH	5,468,658	11/21/95	Burhan BAYRAKTAROGU			
W	AI	5,391,504	02/21/95	Darrell HILL, et al.			
W	AJ	5,249,074	09/28/93	Peter J. TOPHAM			
W	AK	5,239,550	08/24/93	Faquir C. JAIN			
W	AL	5,037,769	08/06/91	Masanori INADA, et al.			
W	AM	4,824,805	04/25/89	Yasutomo KAJIKAWA			
W	AN	4,751,201	06/14/88	Richard N. NOTTENBURG, et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
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	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

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Nym ✓ Ny

Date Considered

5-14-02

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

31002 U.S. PTO
09/02/01
04/02/01

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	AN			
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	AP			

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	Submicron Lateral Scaling of Vertical-Transport Devices: Transferred-Substrate Bipolar Transistors and Schottky-Collector Tunnel Diodes; M. Rodwell, et al.; Invited Paper, 1997 ISA Ultrafast Electronics and Optoelectronics Conference
AR	A 277-GHz f_{max} Transferred-Substrate Heterojunction Bipolar Transistor; B. Agarwal, et al.; IEEE Electron Device Letters, Vol. 18, No. 5, May 1997, pgs. 228-231
AS	Transferred Substrate Schottky-Collector Heterojunction Bipolar Transistors: First Results and Scaling Laws for High f_{max} ; U. Bhattacharya, et al.; IEEE Electron Device Letters, Vol. 16, No. 8, August 1995, pgs. 357, 359
AT	A > 400 GHz f_{max} Transferred-Substrate HBT Integrated Circuit Technology; R. Pullala, et al.; DRC 1997
AU	Deep Submicron Transferred-Substrate Heterojunction Bipolar Transistors; Q. Lee, et al.; DRC 1998
AV	170 GHz Transferred-Substrate Heterojunction Bipolar Transistor; U. Bhattacharya, et al.; Electronics Letters, 18th July 1996, Vol. 32, No. 15, pgs. 1405-6
AW	Transferred Substrate Heterojunction Bipolar Transistors; Dissertation by U. Bhattacharya, Nov. 27, 1996
AX	Digital Integrated Circuits in the Transferred-Substrate HBT Technology; Dissertation by R. Pullala, June 1998

EXAMINER

N/A

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
NY	AA	5,318,916	06/07/94	ENQUIST ET AL.	—	—	
	AB						
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	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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